

ITS42008-SB-D

Smart Octal High-Side NMOS-Power Switch

Data Sheet

Rev 1.01, 2014-05-19

Standard Power



Smart Octal High-Side NMOS-Power Switch

ITS42008-SB-D



1 Overview

Features

- Programmable Input thresholds: CMOS or $V_{\rm S}$ / 2
- Switching all types of resistive, inductive and capacitive loads
- Fast demagnetization of inductive loads
- · Very low standby current
- Optimized Electromagnetic Compatibility (EMC)
- Constant current source diagnostic output for overtemperature
- Overload protection
- Undervoltage shutdown with hysteresis
- Current limitation
- Short circuit protection
- · Thermal shutdown with restart
- Overvoltage protection (including load dump)
- Reverse battery protection with external resistor
- · Loss of GND and loss of Vbb protection
- Electrostatic Discharge Protection (ESD)
- Green Product (RoHS compliant)

ITS42008-SB-D is not qualified and manufactured according to the requirements of Infineon Technologies with regards to automotive and/or transportation applications.

Description

The ITS42008-SB-D is a protected $200m\Omega$ Smart Octal High-Side NMOS-Power Switch in a PG-DSO-36 power package with charge pump, CMOS or supply-rationmetric compatible input and constant current diagnostic feedback indicating overtemperature of the device.

Product Summary

Overvoltage protection V_{SAZmin} = 47V Operating voltage range: 11V < V_S < 45V On-state resistance R_{DSON} = typ 150m Ω Operating Temperature range: Tj = -25°C to 125°C

Application

- All types of resistive, inductive and capacitive loads.
- Driver for electromagnetic relays
- Power switch for 12V, 24V and 42V DC applications with CMOS compatible or high voltage control interface
- Micro controller or opto coupler compatible power switch with diagnosis feedback for overtemperature
 - Power managment for high-side-switching with low current consumption in OFF-mode

Туре	Package	Marking
ITS42008-SB-D	PG-DSO-36	I2008D

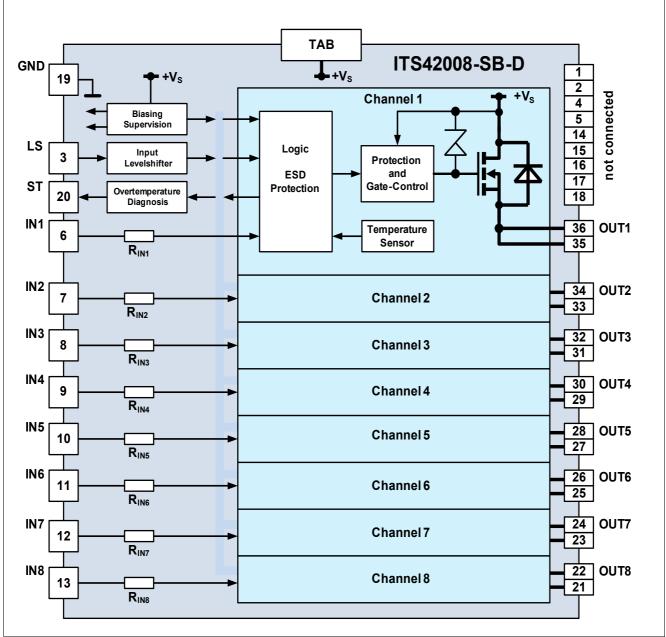


PG-DSO-36



Block Diagram and Terms

2 Block Diagram and Terms







ITS42008-SB-D

Block Diagram and Terms

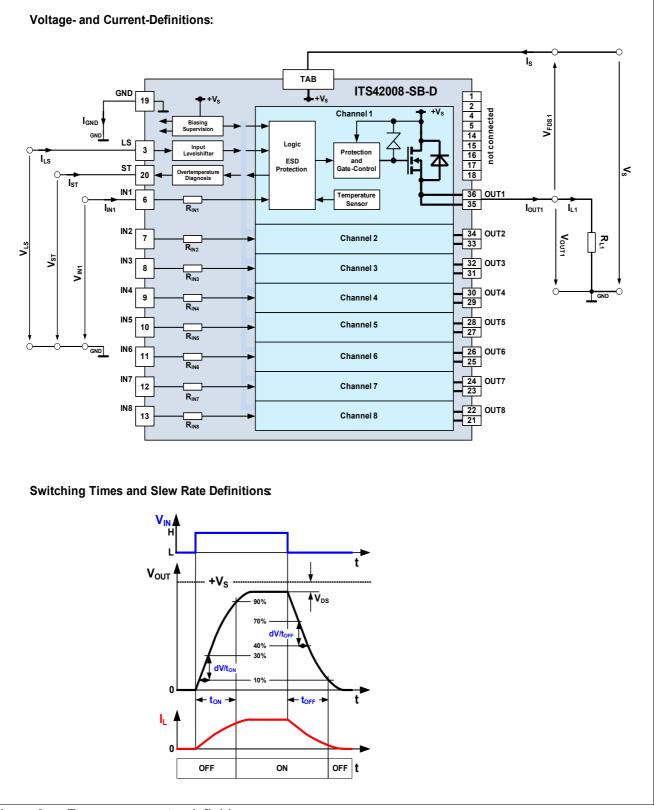


Figure 2 Terms - parameter definition



Pin Configuration

3 Pin Configuration

3.1 Pin Assignment

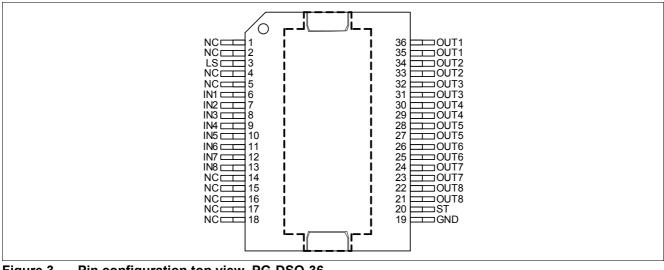


Figure 3 Pin configuration top view, PG-DSO-36

3.2 Pin Definitions and Functions

Pin	Symbol	Function
1, 2, 4, 5	NC	not connected
3	LS	Input level progamming pin; Level: CMOS if LS=L; VS/2 if LS=H
6	IN1	Input channel 1, controles the power switch; the powerswitch is ON when IN1=H
7	IN2	Input channel 2, controles the power switch; the powerswitch is ON when IN2=H
8	IN3	Input channel 3, controles the power switch; the powerswitch is ON when IN3=H
9	IN4	Input channel 4, controles the power switch; the powerswitch is ON when IN4=H
10	IN5	Input channel 5, controles the power switch; the powerswitch is ON when IN5=H
11	IN6	Input channel 6, controles the power switch; the powerswitch is ON when IN6=H
12	IN7	Input channel 7, controles the power switch; the powerswitch is ON when IN7=H
13	IN8	Input channel 8, controles the power switch; the powerswitch is ON when IN8=H
14, 15, 16, 17, 18	NC	not connected
19	GND	Logic ground
20	ST	Status output (common diagnostic output); current source on in case of overtemperature; integrated pull down resistor to GND
21 and 22	OUT8	Output to the load of channel 8 (source of the DMOS power switch)
23 and 24	OUT7	Output to the load of channel 7 (source of the DMOS power switch)
25 and 26	OUT6	Output to the load of channel 6 (source of the DMOS power switch)
27 and 28	OUT5	Output to the load of channel 5 (source of the DMOS power switch)





Pin Configuration

Pin	Symbol	Function
29 and 30	OUT4	Output to the load of channel 4 (source of the DMOS power switch)
31 and 32	OUT3	Output to the load of channel 3 (source of the DMOS power switch)
33 and 34	OUT2	Output to the load of channel 2 (source of the DMOS power switch)
35 and 36	OUT1	Output to the load of channel 1 (source of the DMOS power switch)
ТАВ	VS	Supply voltage (design the wiring for the maximum short circuit current and also for low thermal resistance)



General Product Characteristics

4 General Product Characteristics

4.1 Absolute Maximum Ratings

Table 1Absolute maximum ratings $^{1)}$ at $T_j = 25^{\circ}$ C unless otherwise specified. Currents flowing into the
device unless otherwise specified in chapter "Block Diagram and Terms"

Parameter	Symbol	Values			Unit	Note /	Number
		Min.	Тур.	Max.		Test Conditi on	
Supply voltage VS							
Voltage	Vs			45	V		4.1.1
Voltage for short circuit protection	V _{SSC}			Vs	V		4.1.2
Output stage OUTx				-			
Output Current; (Short circuit current see electrical characteristics)	I _{OUTx}	- 2			A	self limited	4.1.3
Reverse current through GND	1			1			1
Current	$I_{\rm RGND}$			1.6	А	self limited	4.1.4
Input INx (channel 1 to 8)	-+	1					+
Voltage	V _{INx}	- 10		Vs	V		4.1.5
Current	$I_{\rm IN}$	- 5		5	mA		4.1.6
Input level progamming LS	4	1				-	-1
Voltage	$V_{\rm LS}$	- 1		Vs	V		4.1.7
Status ST		4					
Voltage	ILS	- 0.3			V	self limited	4.1.8
Current	ILS			1	mA	self limited	4.1.9
Temperatures							
Junction Temperature	Tj	-40		125	°C		4.1.10
Storage Temperature	T _{stg}	-55		125	°C		4.1.11
Power dissipation						·	
Ta = 25 °C ²⁾	P _{tot}			3.3	W		4.1.12
Inductive load switch-off energy dissipation				I			-
Tj = 125 °C; IL= 625mA ¹⁾ ; all channels active	E _{AS}			1	J	single pulse	4.1.13
Tj = 125 °C; IL= 625mA ¹⁾ ; one channel	E _{AS}			10	J	single pulse	4.1.14
active							
ESD Susceptibility							
ESD susceptibility (pins INx; LS and ST)	V_{ESD}	-1		1	kV	HBM ³⁾	4.1.15
ESD susceptibility (all other pins)	V_{ESD}	-5		5	kV	HBM ³⁾	4.1.16

1) Not subject to production test, specified by design

2) Device on 50mm*50mm*1.5mm epoxy PCB FR4 with 6 cm2 (one layer, 70mm thick) copper area for Vbb connection. PCB is vertical without blown air

3) ESD susceptibility HBM according to EIA/JESD 22-A 114.



General Product Characteristics

Note: Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Integrated protection functions are designed to prevent IC destruction under fault conditions described in the data sheet. Fault conditions are considered as "outside" the normal operating range. Protection functions are neither designed for continuous nor repetitive operation.

4.2 Functional Range

Table 2 Functional Range

Parameter	Symbol	Values		Unit	Note /	Number	
		Min.	Тур.	Max.		Test Condition	
Nominal Operating Voltage	Vs	11		45	V	$V_{\rm S}$ increasing	4.2.1

Note: Within the functional range the IC operates as described in the circuit description. The electrical characteristics are specified within the conditions given in the related electrical characteristics table.

4.3 Thermal Resistance

Note: This thermal data was generated in accordance with JEDEC JESD51 standards. For more information, go to **www.jedec.org**.

Parameter	Symbol		Values	5	Unit	Note / Test Condition	Number
		Min.	Тур.	Max.			
Thermal Resistance - Junction to tab	R _{thj-tab}		2.8		K/W		4.3.1
Thermal Resistance - Junction to Ambient - 1s0p, minimal footprint	R _{thJA_1s0p}		44.1		K/W	2)	4.3.2
Thermal Resistance - Junction to Ambient - 1s0p, 300mm ²	R _{thJA_1s0p_300mm}		26.5		K/W	3)	4.3.3
Thermal Resistance - Junction to Ambient - 1s0p, 600mm ²	$R_{\rm thJA_1s0p_600mm}$		23.8		K/W	4)	4.3.4
Thermal Resistance - Junction to Ambient - 2s2p	R _{thJA_2s2p}		19.9		K/W	5)	4.3.5
Thermal Resistance - Junction to Ambient with thermal vias - 2s2p	R _{thJA_2s2ptv}		18.8		K/W	6)	4.3.6

1) Not subject to production test, specified by design

 Specified R_{thJA} value is according to Jedec JESD51-3 at natural convection on FR4 1s0p board, footprint; the Product (Chip+Package) was simulated on a 76.2 x 114.3 x 1.5 mm board with 1x 70µm Cu.

 Specified R_{thJA} value is according to Jedec JESD51-3 at natural convection on FR4 1s0p board, Cu, 300mm²; the Product (Chip+Package) was simulated on a 76.2 x 114.3 x 1.5 mm board with 1x 70µm Cu.

 Specified R_{thJA} value is according to Jedec JESD51-3 at natural convection on FR4 1s0p board, 600mm²; the Product (Chip+Package) was simulated on a 76.2 x 114.3 x 1.5 mm board with 1x 70μm Cu.

5) Specified *R*_{thJA} value is according to Jedec JESD51-2,-5,-7 at natural convection on FR4 2s2p board; the Product (Chip+Package) was simulated on a 76.2 x 114.3 x 1.5 mm board with 2 inner copper layers (2 x 70μm Cu, 2 x 35μm Cu).



General Product Characteristics

6) Specified R_{thJA} value is according to Jedec JESD51-2,-5,-7 at natural convection on FR4 2s2p board with two thermal vias; the Product (Chip+Package) was simulated on a 76.2 x 114.3 x 1.5 mm board with 2 inner copper layers (2 x 70µm Cu, 2 x 35µm Cu. The diameter of the two vias are equal 0.3mm and have a plating of 25um with a copper heatsink area of 3mm x 2mm). JEDEC51-7: The two plated-through hole vias should have a solder land of no less than 1.25 mm diameter with a drill hole of no less than 0.85 mm diameter.



Electrical Characteristics

5 Electrical Characteristics

Table 4 $V_s = 15V$ to 30V; Tj = -25°C to 125°C; $V_{LS} = 0V$; all voltages with respect to ground, currents
flowing into the device unless otherwise specified in chapter "Block Diagram and Terms".
Typical values at $V_s = 13.5V$, $T_i = 25°C$; index "x" means "number of channel 1 to 8".

Parameter	Symbol	Values			Unit	Note /	Number
		Min.	Тур.	Max.		Test Condition	
Powerstages				1			
NMOS ON Resistance	R _{DSONx}		150	200	mΩ	I_{OUTx} = 0.5A; T_{j} = 25°C; V_{LS} = V_{INx} = V_{S} =15V	5.0.1
NMOS ON Resistance	R _{DSONx}		270	320	mΩ	$I_{OUTx} = 0.5A;$ $T_j = 125^{\circ}C;$ $V_{LS} = V_{INx} = V_S = 15V$	5.0.2
Timings of Power Stages ¹⁾							
Turn ON Time(to 90% of V_{outx}); L to H transition of V_{INx}	t _{ONx}		50	100	μs	$V_{\rm S}$ =15V; $R_{\rm Lx}$ = 47 Ω	5.0.3
Turn OFF Time (to 10% of V_{outx}); H to L transition of V_{INx}	t _{OFFx}		75	150	μs	$V_{\rm S}$ =15V; $R_{\rm Lx}$ = 47 Ω	5.0.4
ON-Slew Rate (10 to 30% of V_{outx}); L to H transition of V_{INx}	SR _{ONx}		1.0	2.0	V/µs	$V_{\rm S}$ =15V; $R_{\rm Lx}$ =47 Ω	5.0.5
OFF-Slew Rate (70 to 40% of V_{outx}); H to L transition of V_{INx}	SR _{OFFx}		1.0	2.0	V/µs	$V_{\rm S}$ =15V; $R_{\rm Lx}$ = 47 Ω	5.0.6
Under voltage lockout (charge pr	ump start	-stop-re	estart)	1			
Supply undervoltage; charge pump stop voltage	V _{SUV}	7.0		10.5	V	$V_{\rm S}$ decreasing	5.0.7
Supply startup voltage; Charge pump restart voltage	V _{SSU}			11.0	V	$V_{\rm S}$ increasing	5.0.8
Supply undervoltage hysteresis	V _{SUHY}		0.5		V	$V_{\text{SUHY}} = V_{\text{SSU}} - V_{\text{SUV}}$	5.0.9
Current consumption		4	I	1	Į		
Operating current	$I_{\rm GND}$		5	12	mA	$V_{\rm INx} = V_{\rm LS} = V_{\rm S} = 30 \text{V}$	5.0.10
Standby current	I _{SSTB}		50	150	μA	V_{INx} = 6.5V; V_{LS} = V_{S} =15V; V_{OUTx} = 0V	5.0.11
Output leakage current	I _{outlkx}		5	10	μA	V_{INx} = 6.5V; V_{LS} = V_{S} =15V V_{OUTx} = 0V	5.0.12
Protection functions ²⁾	•	ł		+		•	
Initial peak short circuit current limit	I _{LSCPx}			1.9	A	$T_{\rm j}$ = -25°C $V_{\rm LS}$ = $V_{\rm S}$ = $V_{\rm INx}$ = 30V; $t_{\rm mx}$ = 700µs	5.0.13



Electrical Characteristics

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flowing into the device unless otherwise specified in chapter "Block Diagram and Terms".
Typical values at V_s = 13.5V, T_i = 25°C; index "x" means "number of channel 1 to 8".

Parameter	Symbol		Value	S	Unit	Note /	Number
	-	Min.	Тур.	Max.	-	Test Condition	
Initial peak short circuit current limit	I _{LSCPx}		1.4		A	$T_{\rm j}$ = 25°C $V_{\rm LS}$ = $V_{\rm S}$ = $V_{\rm INx}$ = 30V; $t_{\rm mx}$ = 700µs	5.0.14
Initial peak short circuit current limit	I _{LSCPx}	0.7			A	$T_{\rm j}$ = 125°C $V_{\rm LS}$ = $V_{\rm S}$ = $V_{\rm INx}$ = 30V; $t_{\rm mx}$ = 700µs	5.0.15
Repetitive short circuit current limit $T_j = T_{jTrip}$; see timing diagrams	$I_{\rm LSCRx}$		1.1		A	$V_{\rm INx}$ = 5.0V;	5.0.16
$\overline{\text{Output clamp at } V_{\text{OUTx}} = V_{\text{S}} - V_{\text{DSCLx}}}$ (inductive load switch off)	V _{DSCLx}	47	53	60	V	I_{OUTx} = 4mA; V_{LS} =30V	5.0.17
Overvoltage protection	V _{SAZ}	47			V	$I_{\rm S}$ = 4mA $V_{\rm LS}$ =30V	5.0.18
Thermal overload trip temperature	$T_{\rm jTrip}$	135			°C		5.0.19
Thermal hysteresis	T _{HYS}		10		к		5.0.20
Reverse Battery ³⁾							
Continuous reverse battery voltage	V_{SREV}			45	V		5.0.21
Forward voltage of the drain- source reverse diode	V_{FDSx}			1.2	V	<i>I</i> _{FDS} = 1.25A; <i>V</i> _{IN} = 0V	5.0.22
Input interface; pin INx	1	1	ļ	ł	1		
Input turn-ON threshold voltage	V _{INONx}	2.2			V	LS = L; CMOS mode	5.0.23
Input turn-OFF threshold voltage	V_{INOFFx}			0.8	V	LS = L; CMOS mode	5.0.24
Input turn-ON threshold voltage	V _{INONx}	V _{ST} / 2 + 1			V	LS = H or open; ratiometric mode	5.0.25
Input turn-OFF threshold voltage	V_{INOFFx}			V _{ST} / 2 - 1	V	LS = H or open; ratiometric mode	5.0.26
Input threshold hysteresis	VINHYSX		0.3		V		5.0.27
Off state input current	I _{INOFFx}	8			μA	LS = L; CMOS mode V_{INx} = 0.8V	5.0.28
On state input current	I _{INONx}			70	μA	LS = L; CMOS mode $V_{INx} = 2.2V$	5.0.29
Off state input current	I _{INOFFx}	80			μA	LS = H or open; ratiometric mode $V_{INx} = V_{ST} / 2 - 1$	5.0.30
On state input current	I _{INONx}			260	μA	LS = H or open; ratiometric mode $V_{INx} = V_{ST} / 2 + 1$	5.0.31
Input switch ON delay time	t _{dON}	150	340		μs		5.0.32



Electrical Characteristics

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flowing into the device unless otherwise specified in chapter "Block Diagram and Terms".
Typical values at V_s = 13.5V, T_i = 25°C; index "x" means "number of channel 1 to 8".

Parameter	Symbol	Values			Unit	Note /	Number
		Min.	Тур.	Max.		Test Condition	
Input resistance	R _{INx}	2	3	5	kΩ		5.0.33
Input interface; pin LS				1			I
Pull down resistance	R _{LS}	300	800		kΩ	$V_{\rm LS} = V_{\rm S} = 15 \rm V$	5.0.34
Status output (current sour	rce); pin ST	1		1			
Status output current	I _{ST}	2	3	4	mA	$V_{\rm ST}$ = 5V $V_{\rm LS}$ = $V_{\rm S}$ =30V	5.0.35
Status leakage current	I _{STLK}	- 2			μA	$V_{ST} = 0V;$ $T_j < 135^{\circ}C;$ $V_{LS} = V_S = 30V$	5.0.36

1) Timing values only with high slewrate input signal; otherwise slower.

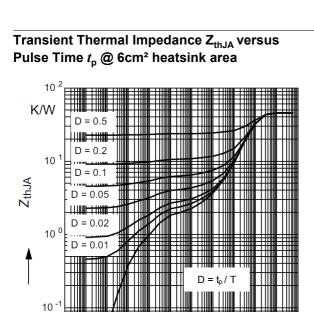
 Integrated protection functions are designed to prevent IC destruction under fault conditions described in the data sheet. Fault conditions are considered as "outside" normal operating range. Protection functions are not designed for continuous repetitive operation.

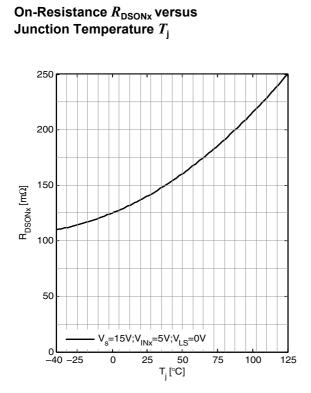
 Requires a 150W resistor in GND connection. The reverse load current trough the intrinsic drain-source diode of the power-M



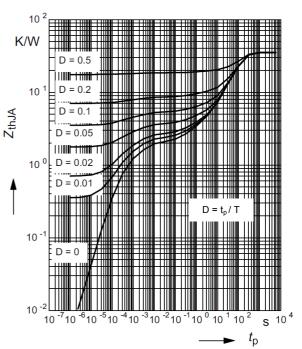
6 Typical Performance Graphs

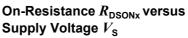
Typical Characterisitics

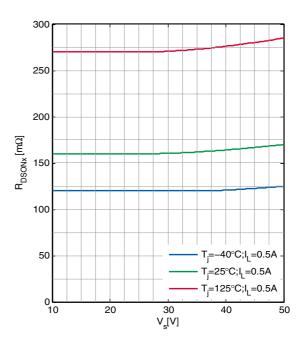




Transient Thermal Impedance Z_{thJA} versus Pulse Time t_p @ min footprint







10 ⁻²

10⁻⁷10⁻⁶10⁻⁵10⁻⁴10⁻³10⁻²10⁻¹10⁰10¹10

s ¹⁰⁴

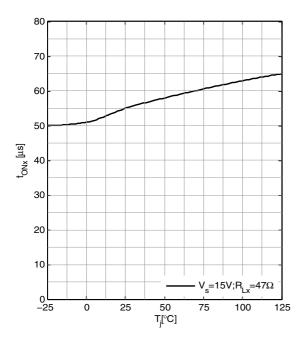
tp



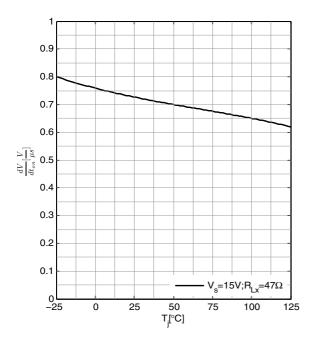


Typical Characterisitics

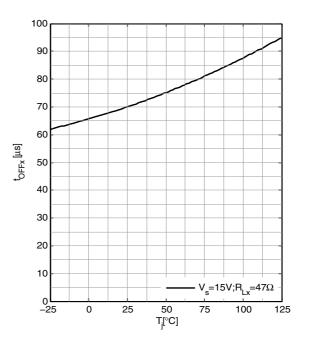
Switch ON Time t_{ONx} versus Junction Temperature T_i



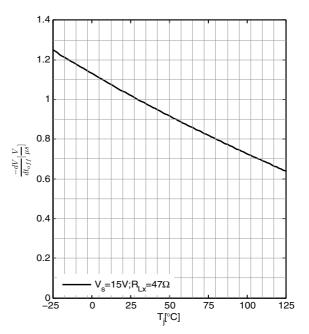
ON Slewrate SR_{ONx} versus Junction Temperature T_i



Switch OFF Time t_{OFFx} versus Junction Temperature T_i



OFF Slewrate SR_{OFFx} versus Junction Temperature T_i



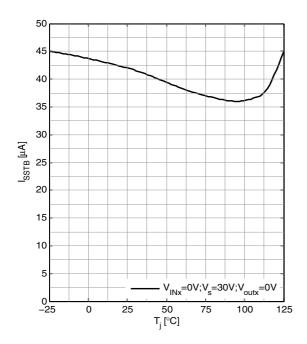


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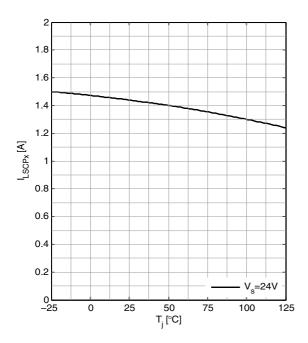
Typical Performance Graphs

Typical Characterisitics

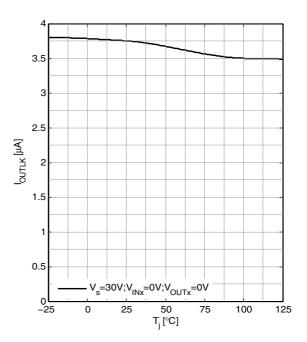
Standby Current I_{SSTB} versus Junction Temperature T_{i}



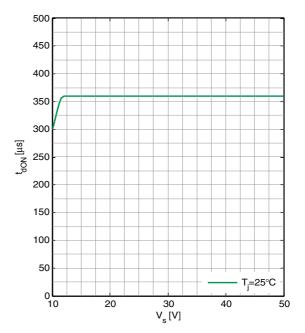
Junction Temperature T_i



Output Leakage current I_{OUTLKx} versus Junction Temperature T_i



Initial Peak Short Circuit Current Limt I_{LSCPx} versus Initial Short Circuit Shutdown time t_{dON} versus Junction Temperature T_i

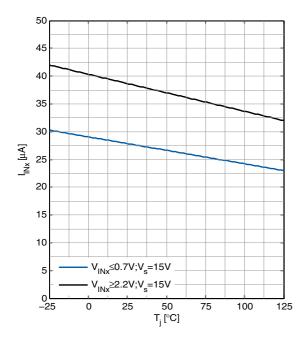




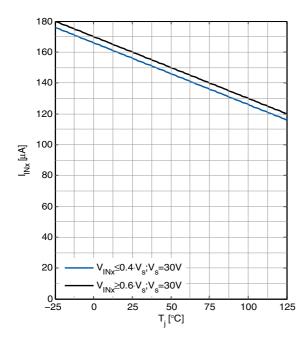


Typical Characterisitics

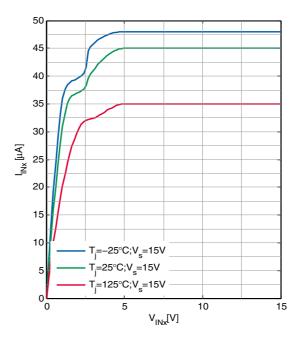
Input Current Consumption $I_{\rm INx}$ versus Junction Temperature $T_{\rm j}$



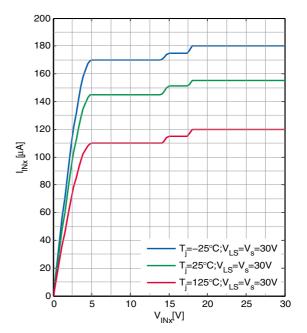
Input Current Consumption I_{INx} versus Junction Temperature T_i



Input Current Consumption $I_{\rm INx}$ versus Input voltage $V_{\rm IN}$



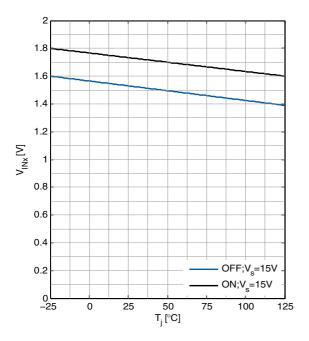
Input Current Consumption $I_{\rm INx}$ versus Input voltage $V_{\rm IN}$



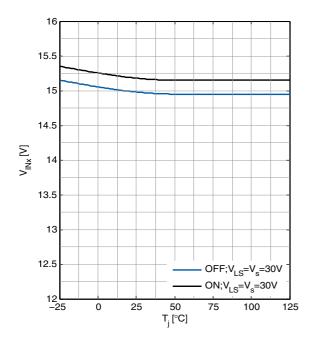


Typical Characterisitics

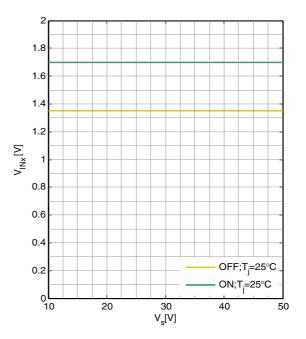
Input Threshold voltage $V_{\rm INH,Lx}$ versus Junction Temperature $T_{\rm j}$



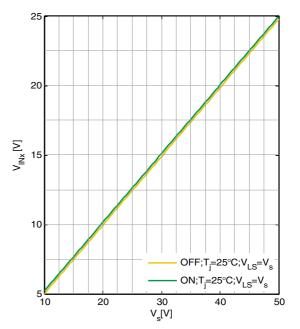
Input Threshold voltage $V_{\rm INH,Lx}$ versus Junction Temperature $T_{\rm i}$



Input Threshold voltage $V_{\rm INH,Lx}$ versus Supply Voltage $V_{\rm S}$



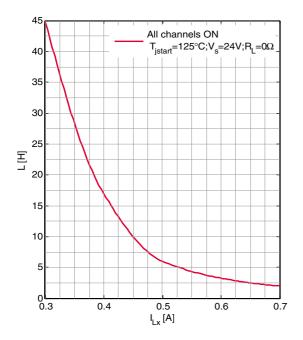
Input Threshold voltage $V_{\rm INH,Lx}$ versus Supply Voltage $V_{\rm S}$



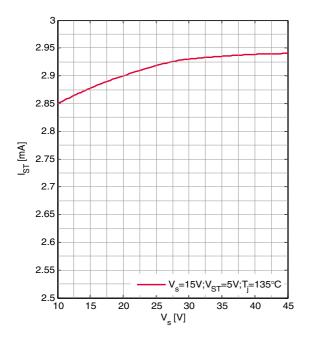


Typical Characterisitics

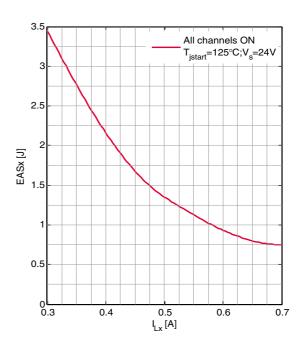
Max. allowable Load Inductance L versus Load current $I_{\rm Lx}$



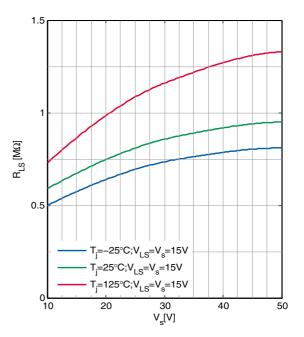
Status Output Current $I_{\rm ST}$ versus Supply Voltage $V_{\rm S}$



Max. allowable Inductive single pulse Switch-off Energy $E_{\rm AS}$ versus Load current $I_{\rm Lx}$



Internal pull down Resistor $R_{\rm LS}$ at pin LS versus Supply Voltage $V_{\rm S}$





7.1 Application Diagram

The following information is given as a hint for the implementation of the device only and shall not be regarded as a description or warranty for a certain functionality, condition or quality of the device.

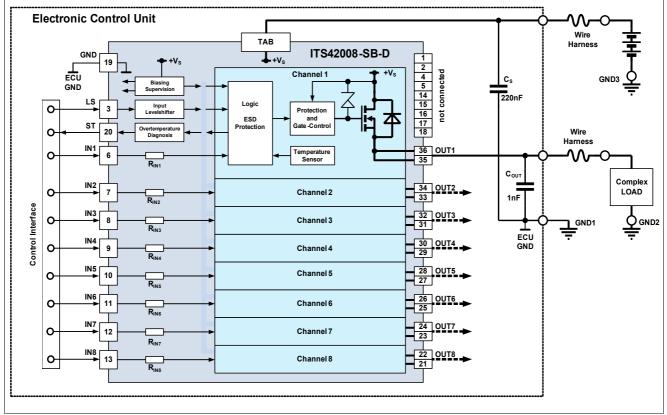


Figure 4 Application Diagram

The ITS42008-SB-D can be connected directly to the battery of a supply network. It is recommended to place a ceramic capacitor (e.g. $C_s = 220$ nF) between supply and GND of the ECU to avoid line disturbances. Wire harness inductors/resistors are sketched in the application circuit above.

The complex load (resistive, capacitive or inductive) must be connected to the output pin OUT.

A built-in current limit protects the device against destruction.

The ITS42008-SB-D can be switched on and off with ground related standard logic signal at pin INx if the level programming pin LS is set to L.

If LS is connected to the supply voltage $V_{\rm S}$ the input threshold is set to ~ 50% of $V_{\rm S}$.

To achieve a higher robustness it is recommended to connect the LS pin to GND or Supply voltage.

If the pin LS is left open the thresholds are automatically set to CMOS level caused by an internal high ohmic pull down resistor to GND.

In standby mode (all inputs INx=L) the ITS42008-SB-D is deactivated with very low current consumption.

The output voltage slope is controlled during on and off transistion to minimize emissions. Only a small ceramic capacitor COUT=1nF is recommended to attenuate RF noise.



In the following chapters the main features, some typical waverforms and the protection behaviour of the ITS42008-SB-D is shown. For further details please refer to application notes on the Infineon homepage.

7.2 Diagnosis Description

For diagnostic purpose the device provides a digital output pin ST in order to indicate fault conditions.

The status output (ST) of the ITS42008-SB-D is a high voltage current source.

In "normal" operation mode (no overtemperature) the current source is switched OFF. An internal pull down resistor pulls pin ST down to GND. In case of overtemperature the current source is activated. To limit the voltage at pin ST an external zenerdiode to GND must be added.

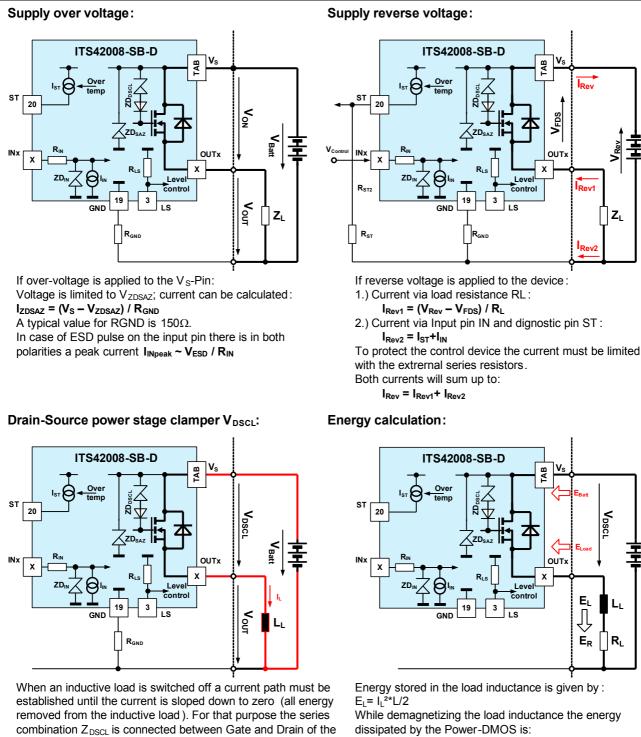
The following truth table defines the status output.

Device Operation	INx	OUTx	current source at ST	Comment
Normal Operation	L	L	OFF	
Normal Operation	Н	Н	OFF	
Short circuit to GND	L	L	OFF	
Short circuit to GND	Н	L	OFF	
Undervoltage at V _S	L	L	OFF	
Undervoltage at V _S	Н	L	OFF	
Overtemperature	L	L	OFF	
Overtemperature	Н	L	ON	toggeling with restart

Table 5 Truth Table of diagnosis feature



7.3 **Special Feature Description**



 $E_{AS} = E_S + E_L - E_R$

With an approximate solution for $R_L = 0\Omega$: $E_{AS} = \frac{1}{2} * L * I_{L}^{2} * \{(1 - V_{S} / (V_{S} - V_{DSCL}))\}$

power DMOS acting as an active clamp.

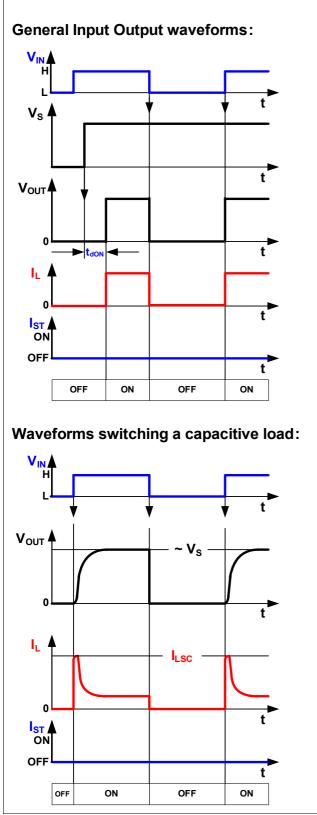
When the device is switched off, the voltage at OUT turns negative until V_{DSCL} is reached.

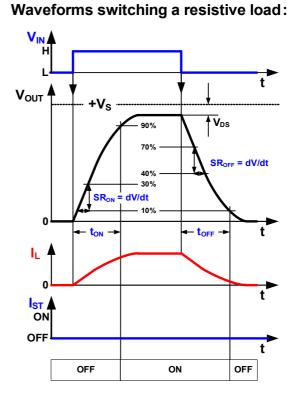
The voltage on the inductive load is the difference between V_{DSCL} and V_{S} .

Figure 5 Special feature description



7.4 Typical Application Waveforms





Waveforms switching an inducitive load :

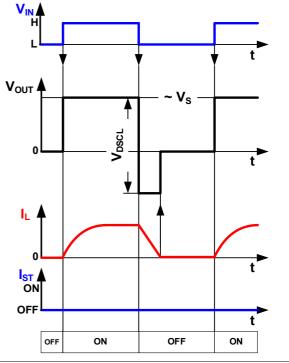
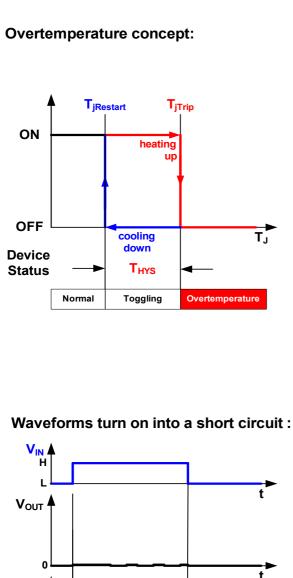


Figure 6 Typical application waveforms of the ITS42008-SB-D



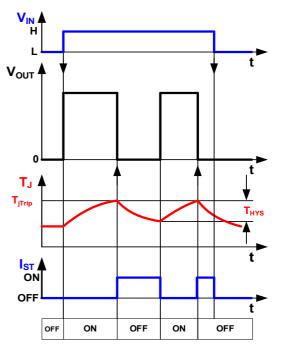
7.5 Protection Behavior



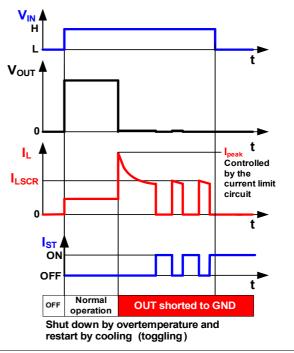
t L ILSCP Controlled by the **I**LSCR current limit circuit 0 ISCOF IST / ON OFF t OFF Overloaded OFF Shut down by overtemperature and restart by cooling (toggling)



Overtemperature behavior:



Waveforms short circuit during on state :





Package outlines and footprint

8 Package outlines and footprint

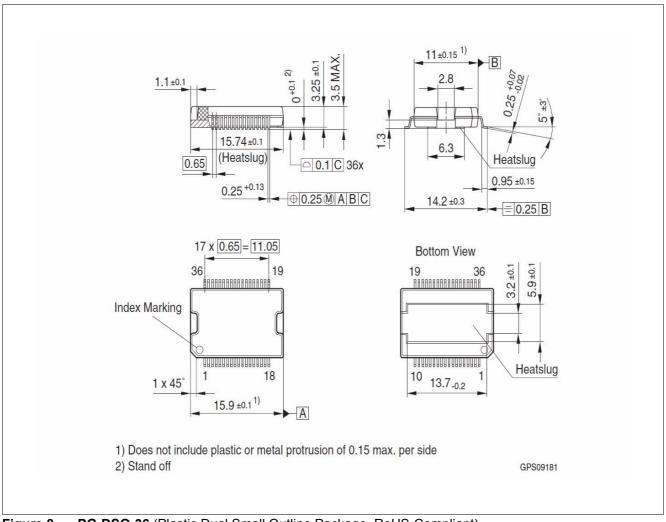


Figure 8 PG-DSO-36 (Plastic Dual Small Outline Package, RoHS-Compliant)

To meet the world-wide customer requirements for environmentally friendly products and to be compliant with government regulations the device is available as a green product. Green products are RoHS-Compliant (i.e Pb-free finish on leads and suitable for Pb-free soldering according to IPC/JEDEC J-STD-020



9 Revision History

Revision	Date	Changes
v 1.01	14-05-19	Datasheet release Editorial Change on Page 11 Temperature conditions for lines 5.0.14 and 5.0.15 were corrected to 25°C and
v 1.0	12-09-01	125°C respectively Datasheet release

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